

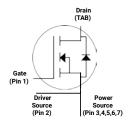
Silicon Carbide Power C3M™ MOSFET Technology N-Channel Enhancement Mode

Features

- 3rd generation Silicon Carbide (SiC) MOSFET technology
- Optimized package with separate driver source pin
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q_{rr})
- Halogen free, RoHS compliant







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Part Number	Package	Marking
C3M0032120J1	TO 263-7L XL	C3M0032120J1

Applications

- Solar inverters
- EV motor drive
- High voltage DC/DC converters
- Switched mode power supplies
- Load switch

Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

Key Parameters

Parameter	Symbol	Min.	Тур.	Max	Unit	Conditions	Note
Drain - Source Voltage	V _{DS}			1200		T _c = 25°C	
Maximum Gate - Source Voltage	V _{GS(max)}	-8		+19	v	Transient	
Operational Gate-Source Voltage	V _{GS op}		-4/15			Static	Note 1
DC Continuous Drain Current				68		$V_{GS} = 15 \text{ V}, T_{C} = 25 \text{ °C}, T_{J} \le 150 \text{ °C}$	Fig. 19
	l _D			44	A	$V_{GS} = 15 \text{ V}, T_{C} = 100 \text{ °C}, T_{J} \le 150 \text{ °C}$	Note 2
Pulsed Drain Current	I _{DM}			120		$t_{p_{max}}$ limited by $T_{j_{max}}$ $V_{GS} = 15V, T_{C} = 25 ^{\circ}C$	Fig. 22
Power Dissipation	P _D			277	w	$T_{c} = 25^{\circ}C, T_{J} = 150^{\circ}C$	Fig. 20
Operating Junction Temperature	T,			-40 to +175			
Case and Storage Temperature	T_c, T_{stg}			-40 to 150	°C		
Solder Temperature	TL			260		According to JEDEC J-STD-020	

 $Note~(1): Recommended~turn-on~gate~voltage~is~15V~with~\pm 5\%~regulation~tolerance, see~Application~Note~PRD-04814~for~additional~details~tolerance, see~Application~details~tolerance, see~Application~d$

Note (2): Verified by design

Electrical Characteristics ($T_c = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Conditions	Note	
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	1200	_	_		$V_{GS} = 0 \text{ V}, I_{D} = 100 \mu\text{A}$		
Cata Thurshald Walter as	.,	1.8	2.7	3.6	V	$V_{DS} = V_{GS}, I_D = 11.5 \text{ mA}, T_J = 25^{\circ}\text{C}$	F: 44	
Gate Threshold Voltage	$V_{GS(th)}$	_	2.2	_		$V_{DS} = V_{GS}, I_D = 11.5 \text{ mA}, T_J = 150^{\circ}\text{C}$	Fig. 11	
Zero Gate Voltage Drain Current	I _{DSS}	_	1	50	μΑ	V _{DS} = 1200 V, V _{GS} = 0 V		
Gate-Source Leakage Current	I _{GSS}	_	10	250	nA	V _{GS} = 15 V, V _{DS} = 0 V		
Durin Course On Chata Basistan	_	23	32	43		$V_{GS} = 15 \text{ V}, I_D = 41.4 \text{ A}, T_J = 25^{\circ}\text{C}$	Fig. 4,	
Drain-Source On-State Resistance	R _{DS(on)}	_	55	_	mΩ	V _{GS} = 15 V, I _D = 41.4 A, T _J = 150°C	5,6	
Towns and other and	_		25		_	$V_{DS} = 20 \text{ V}, I_{DS} = 41.4 \text{ A}, T_{J} = 25^{\circ}\text{C}$	Fig. 7	
Transconductance	g fs	_	24	_	S	$V_{DS} = 20 \text{ V}, I_{DS} = 41.4 \text{ A}, T_{J} = 175^{\circ}\text{C}$		
Input Capacitance	C _{iss}	_	3424	_			Fig. 17, 18	
Output Capacitance	C _{oss}	_	133	_	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 1000 \text{ V}$		
Reverse Transfer Capacitance	C _{rss}	_	11	_		$f = 100 \text{ khz}$ $V_{AC} = 25 \text{ mV}$		
Output Capacitance Stored Energy	E _{oss}	_	72	_	μJ		Fig. 16	
Turn-On Switching Energy (Body Diode FWD)	Eon	_	360	_		$V_{DS} = 800 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V},$	Fig.	
Turn-Off Switching Energy (Body Diode FWD)	E _{off}	_	90	_	μJ	$I_D = 41.4 \text{ A}, R_{G(ext)} = 2.5 \Omega,$ $L = 99 \mu H$	26	
Turn-On Delay Time	t _{d(on)}	_	15	_		$V_{DD} = 800 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}$		
Rise Time	t _r	_	16	_		$I_D = 41.4 \text{ A}, R_{G(ext)} = 2.5 \Omega,$	Fig. 27	
Turn-Off Delay Time	t _{d(off)}	_	25	_	ns	L= 99 μH Timing relative to V _{DS}		
Fall Time	t _f	_	7	_		Inductive load		
Internal Gate Resistance	R _{G(int)}	_	1.6	_	Ω	$f = 1 \text{ MHz}, V_{AC} = 25 \text{ mV}$		
Gate to Source Charge	$Q_{\rm gs}$	_	40	_		$V_{DS} = 800 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}$		
Gate to Drain Charge	Q_{gd}	_	28	_	nC	I _D = 41.4 A	Fig. 12	
Total Gate Charge	Qg	_	111	_		Per IEC60747-8-4 pg 21		

Reverse Diode Characteristics ($T_c = 25^{\circ}$ C unless otherwise specified)

Parameter	Symbol	Тур.	Max.	Unit	Test Conditions	Notes
Diode Forward Voltage	V	5.0	_	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	V - 4V -20 A T -25°C	Fig.
Diode Forward Voltage	V _{SD}	4.5	_	V	$V_{GS} = -4 \text{ V}, I_{SD} = 20 \text{ A}, T_{J} = 25^{\circ}\text{C}$	8, 9, 10
Continuous Diode Forward Current	Is	_	49		$V_{GS} = -4 \text{ V}, T_J = 150^{\circ}\text{C}, I_{SD} = 20 \text{ A},$	Note 1
Diode Pulse Current	I _{S, pulse}	_	120	A	V_{GS} = -4 V, pulse width t_P limited by $T_{j max}$	Note 1
Reverse Recovery Time	t _{rr}	13	_	ns		
Reverse Recovery Charge	Qrr	323	_	nC	$V_{GS} = -4 \text{ V}, I_{SD} = 41.4 \text{ A}, V_{R} = 800 \text{ V},$ $di_{z}/dt = 7450 \text{ A}/\mu\text{s}, T_{J} = 150^{\circ}\text{C}$	Note 1
Peak Reverse Recovery Current	I _{RRM}	45	_	Α	,,, p.s, .,	
Reverse Recovery Time	t _{rr}	18	_	ns		
Reverse Recovery Charge	Qrr	164	_	nC	$V_{GS} = -4 \text{ V}, I_{SD} = 41.4 \text{ A}, V_{R} = 800 \text{ V},$ $di_{c}/dt = 2200 \text{ A}/\mu\text{s}, T_{J} = 150^{\circ}\text{C}$	Note 1
Peak Reverse Recovery Current	I _{RRM}	16	_	Α	σ.,	

Thermal Characteristics

Parameter	Symbol	Тур	Unit	Note
Thermal Resistance from Junction to Case	$R_{ heta JC}$	0.45	°C/W	Fig. 21
Thermal Resistance From Junction to Ambient	$R_{\theta JA}$	40	*C/W	Fig. 21

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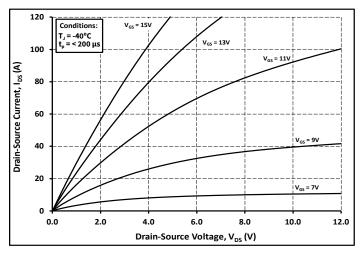


Figure 1. Output Characteristics $T_1 = -40^{\circ}C$

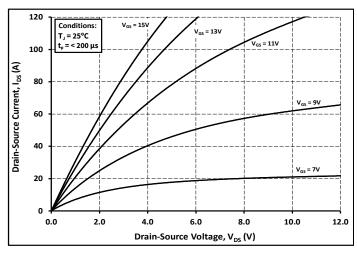


Figure 2. Output Characteristics T_J = 25°C

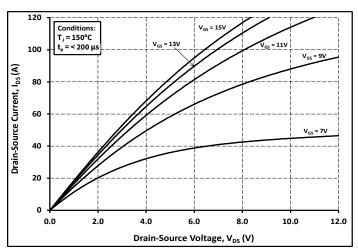


Figure 3. Output Characteristics T_J = 150°C

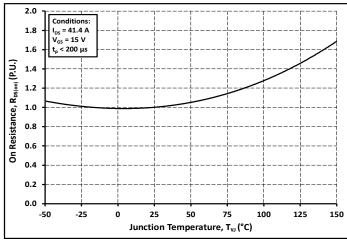


Figure 4. Normalized On-Resistance vs Temperature

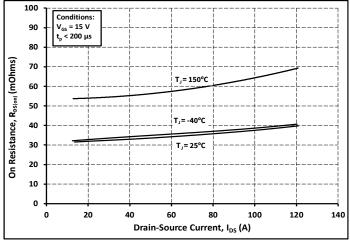


Figure 5. On-Resistance vs Drain Current For Various Temperatures

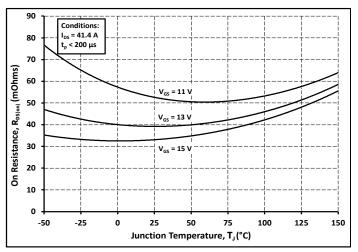


Figure 6. On-Resistance vs Temperature For Various Gate Voltage

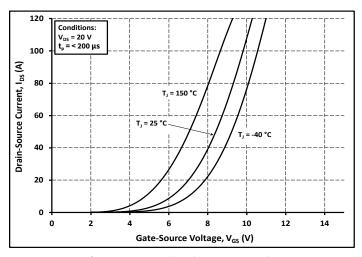


Figure 7. Transfer Characteristic for Various Junction Temperatures

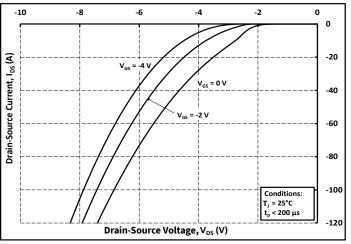


Figure 9. Body Diode Characteristic at 25°C

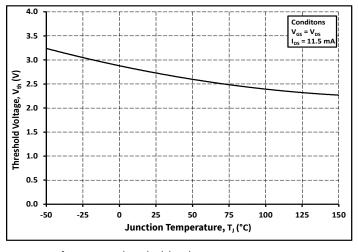


Figure 11. Threshold Voltage vs Temperature

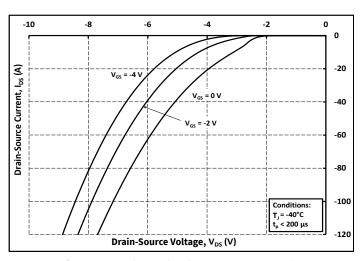


Figure 8. Body Diode Characteristic at -40°C

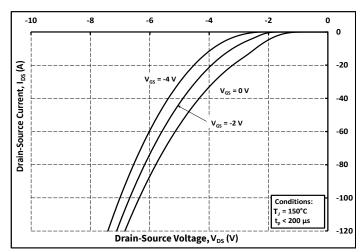


Figure 10. Body Diode Characteristic at 150°C

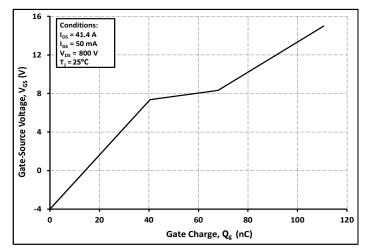


Figure 12. Gate Charge Characteristics

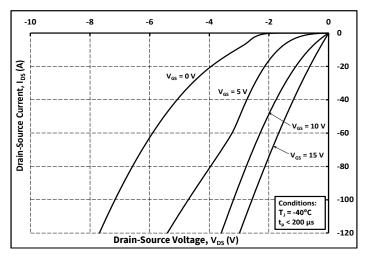


Figure 13. 3rd Quadrant Characteristic at -40°C

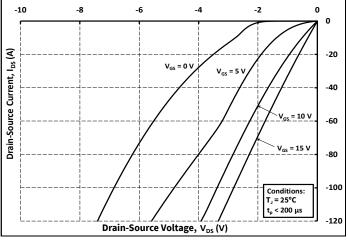


Figure 14. 3rd Quadrant Characteristic at 25°C

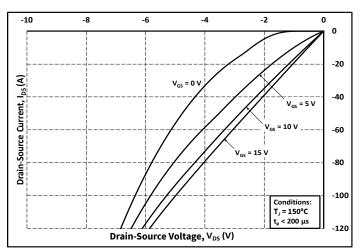


Figure 15. 3rd Quadrant Characteristic at 150°C

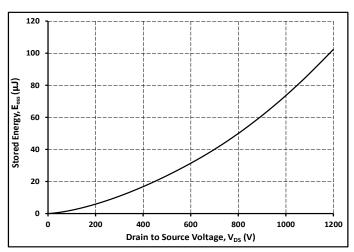


Figure 16. Output Capacitor Stored Energy

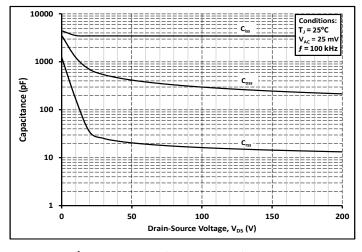


Figure 17. Capacitances vs Drain-Source Voltage (0 - 200 V)

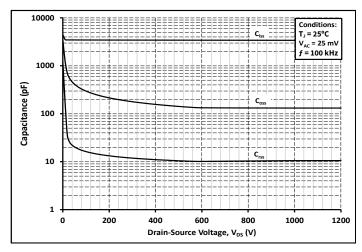


Figure 18. Capacitances vs Drain-Source Voltage (0 - 1200 V)

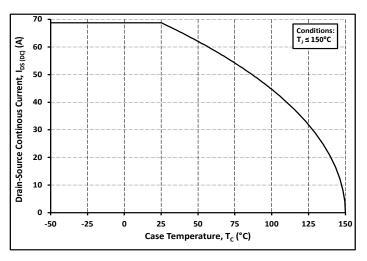


Figure 19. Continuous Drain Current Derating vs Case Temperature

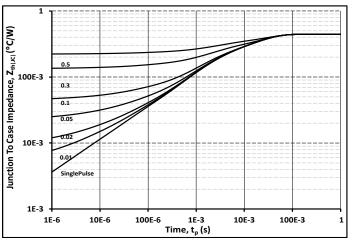


Figure 21. Transient Thermal Impedance (Junction - Case)

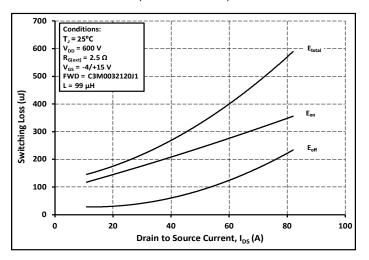


Figure 23. Clamped Inductive Switching Energy vs Drain Current ($V_{DD} = 600 \text{ V}$)

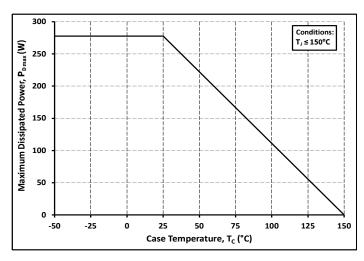


Figure 20. Maximum Power Dissipation Derating vs Case Temperature

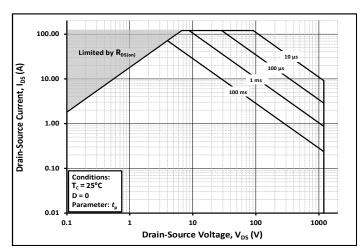


Figure 22. Safe Operating Area

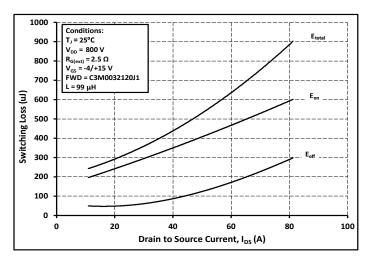


Figure 24. Clamped Inductive Switching Energy vs Drain Current $(V_{DD} = 800 \text{ V})$

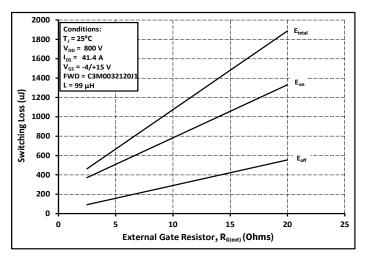


Figure 25. Clamped Inductive Switching Energy vs R_{G(ext)}

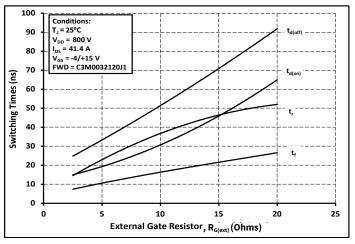


Figure 27. Switching Times vs. R_{G(ext)}

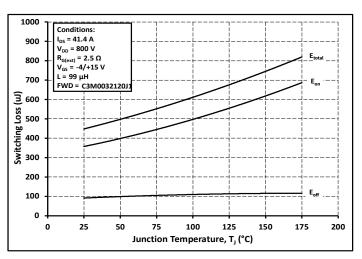


Figure 26. Clamped Inductive Switching Energy vs Temperature

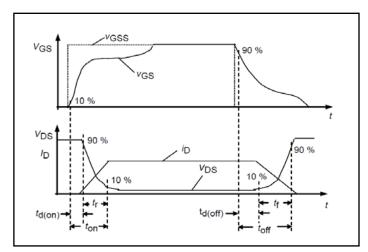


Figure 28. Switching Times Definition

Test Circuit Schematic

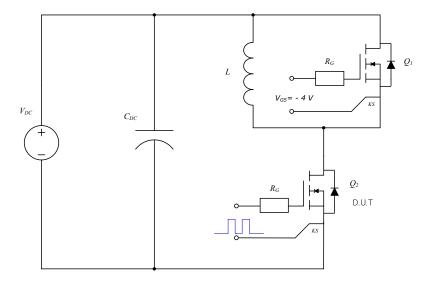
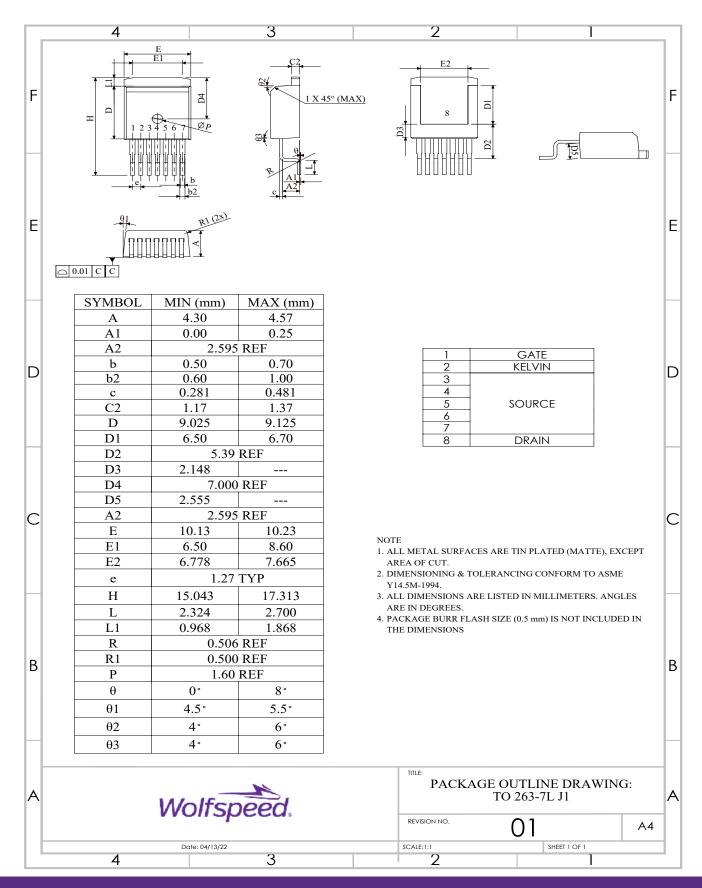


Figure 29. Clamped Inductive Switching Waveform Test Circuit

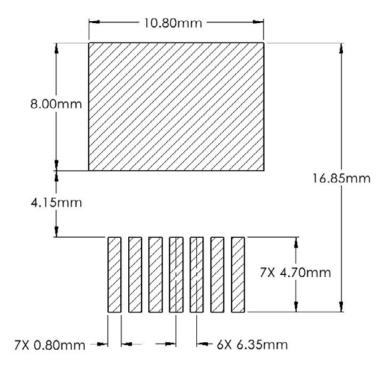
Note:

Turn-off and Turn-on switching energy and timing values measured using SiC MOSFET Body Diode as shown above.

Package Dimensions - Package TO-263-7L XL



Recommended Solder Pad Layout



Revision History

Current Revision	Date of Release	Description of Changes
2	December-2020	N/A
3	December-2023	Updated Wolfspeed branding, package drawing, package image, solder pad layout, added Rev history, Table 1 layout revised

Related Links

- SPICE Models
- SiC MOSFET Isolated Gate Driver reference design
- SiC MOSFET Evaluation Board

Notes & Disclaimer

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The Silicon Carbide MOSFET module switches at speeds beyond what is customarily associated with IGBT-based modules. Therefore, special precautions are required to realize optimal performance. The interconnection between the gate driver and module housing needs to be as short as possible. This will afford optimal switching time and avoid the potential for device oscillation. Also, great care is required to insure minimum inductance between the module and DC link capacitors to avoid excessive VDS overshoot.

RoHS Compliance

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS2), as implemented January 2, 2013. RoHS Declarations for this product can be obtained from your Wolfspeed representative or from the Product Documentation sections of www.wolfspeed.com.

REACh Compliance

REACh substances of high concern (SVHCs) information is available for this product. Since the European Chemical Agency (ECHA) has published notice of their intent to frequently revise the SVHC listing for the foreseeable future, please contact your Wolfspeed representative to ensure you get the most up-to-date REACh SVHC Declaration. REACh banned substance information (REACh Article 67) is also available upon request.

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